## ADVISORY ON THE USE OF THIS DOCUMENT

5 7 .

The information contained in this document has been developed solely for the purpose of providing general guidance to employees of the Goddard Space Flight Center (GSFC). This document may be distributed outside GSFC only as a courtesy to other government agencies and contractors. Any distribution of this document, or application or use of the information contained herein, is expressly conditioned upon, and is subject to, the following understandings and limitations:

- (a) The information was developed for general guidance only and is subject to change at any time;
- (b) The information was developed under unique GSFC laboratory conditions which may differ substantially from outside conditions;
- (c) GSFC does not warrant the accuracy of the information when applied or used under other than unique GSFC laboratory conditions;
- (d) The information should not be construed as a representation of product performance by either GSFC or the manufacturer;
- (e) Neither the United States government nor any person acting on behalf of the United States government assumes any liability resulting from the application or use of the information.

## **UNISYS**

Interoffice Memorandum

Τσ

J Lohr Depaitment

Code 311

K Sahu <sup>r-5</sup> Department

7809 Subject

Radiation Report on CD54HC40103F3A GGS/WIND/WAVES Control No. 5734

Date PPM-92-115

LocatioMarch 20, 1992

Teleph GSFC

Location 31-8954

cc Lanham

E. Werner/406

M. Kaiser/695

G. Robinson/303

A. Sharma/311

\_Library/300.1

A radiation evaluation was performed on CD54HC40103F3A to determine the total dose tolerance of these parts. A brief summary of the test results is provided below. For detailed information, refer to Tables I through IV and Figure 1.

The total dose testing was performed using a cobalt-60 gamma ray source. During the radiation testing, four parts were irradiated under bias (see Figure 1 for bias configuration), and one part was used as a control sample. The total dose radiation steps were 5, 10, 15 and 20 krads\*. After 20 krads, parts were annealed at +25°C for 168 hours and then at +100°C for 168 hours. The dose rate was between 0.05 and 0.12 krads/hour, depending on the total dose level (see Table II for radiation schedule). After each radiation exposure and annealing treatment, parts were electrically tested according to the test conditions and the specification limits listed in Table III. These tests included three functional tests (1 MHz) at 2.0, 4.5 and 6.0V.

All four irradiated parts exceeded the maximum specification limits for ICCH and ICCL after the first radiation exposure to 5 krads. Parts showed increased degradation in ICCH and ICCL on continued irradiation to 10, 15 and 20 krads. Additionally, after 20 krads, all four irradiated parts failed functional test #1 and exceeded the maximum specification limit for VOL1. Parts continued to fail functional test #1 on annealing at 25°C and 100°C, but showed some recovery in ICCH and ICCL.

Table IV provides a summary of the functional test results, as well as the mean and standard deviation values for each parameter after different irradiation exposures and annealing steps.

Any further details about this evaluation can be obtained upon request. If you have any questions, please call me at (301) 731-8954.

\*In this report, the term krads means krads (Si).

## TABLE I. Part Information

Generic Part Number: 54HC40103

GGS/WIND/WAVES
Part Number: CD54HC40103F3A

GGS/WIND/WAVES
Control Number: 5734

Charge Number: C23419

Manufacturer: RCA

Lot Date Code: 8907

Quantity Tested: 5

Serial Numbers of Radiation Samples: 154, 155, 156, 157

Serial Numbers of Control Sample: 153

Part Function: 8-bit down counter

Part Technology: CMOS

Package Style: 16-lead DIP

Test Engineer: Anh Phung

TABLE II. Radiation Schedule for 54HC40103

EVENTS	DATE
1) Initial Electrical Measurements	02/05/92
2) 5 KRAD IRRADIATION (0.12 krads/hour)	02/10/92
POST-5 KRAD ELECTRICAL MEASUREMENT	02/12/92
3) 10 KRAD IRRADIATION (0.12 krads/hour) POST-10 KRAD ELECTRICAL MEASUREMENT	02/12/92 02/14/92
4) 15 KRAD IRRADIATION (0.11 krads/hour) POST-15 KRAD ELECTRICAL MEASUREMENT	02/18/92 02/20/92
5) 20 KRAD IRRADIATION (0.05 KRADS/HOUR)	02/20/92
POST-20 KRAD ELECTRICAL MEASUREMENT	02/24/92
6) 168 HOUR ANNEALING @ 25°C	02/24/92
POST-168 HOUR 25°C ANNEAL ELECTRICAL MEASUREMENT	03/02/92
7) 168 HOUR ANNEALING @ 100°C	03/02/92
POST-168 HOUR 100°C ANNEAL ELECTRICAL MEASUREMENT	03/10/92

all electrical measurements performed at 25°C.

All parts irradiated under bias, see Figure 1.

All annealings performed under bias, see Figure 1.

Table III. Electrical Characteristics of 54HC40103

NO.	PARAMETER	TEST CONDITIONS	MIN 25°C	MAX	UNIT	PINS
1	FONC # 1	Vcc = 2 V VIH = 2.0 V VIL = 0 V f = 1 Mhz				INS, OUT
2	FUNC # 2	Vcc = 4.5 VVIH = 4.5 V VIL = 0 V f = 1 Mhz	ļ	İ		INS, OUT
3	FUNC # 3	Vgc = 6 V VIH = 6.0 V VIL = 0 V f = 1 Mhz				INS, OUT
4	VOH1	Vec = 2 V VIH = 1.5 V VIL = 0.5 V To = -20 UA	1.9		V	OUT
5	VOH2	Vec = 4.5 VVIH = 3.15 VVIL = 1.35 VIo = -20 uA	4.4		V	OUT
6	VOH2	Vcc - 6.0 VVIH - 4.2 V VIL - 1.8 V Io20 uA	5.9		٧	OUT
7	VOH4	Vcc = 4.5 VVIH = 3.15 VVIL = 1.35 VIO = -4.0 mA	3.98		V	OUT
8	VOH5	Vcc = 6.0 VVIH = 4.2 V VIL = 1.8 V Io = -5.2 mA	5.48		٧	001
9	VOLI	Vcc = 2.0 VVIH = 1.5 V VIL = 0.5 V To = +20 uA	0	0.1	٧	CUT
10	VOL2	Vcc = 4.5 VVIH = 3.15 VVIL = 1.35 VIo = +20 uA	0	0,1	V	OUT
11	VOL3	Vcc = 6.0 VVIH = 4.2 V VIL = 1.8 V To = +20 UA	0	0,1	V	OUT
12	. VOL4	Vcc = 4.5 VVIH = 3.15 VVIL = 1.35 Io = +4.0 mA	0	0.26	v	OUT
13	VOL5	Vcc - 6.0 VVIH - 4.2 V VIL = 1.8 V Io - +5.2 mA	0	0.26	V	OUT
14	IIR	Vcc = 6.0 VVIH - 6.0 V VIL = 0	0	100	ΩA	INS
15	IIL	Vcc = 6.0 VIH = 6.0 V VIL = 0	-100	C	пA	INS
16	ICCH	Vcc = 6.0 VVIH - 6.0 V VIL - 0	0	8	uА	Voc
17	ICCL	Vec = 6.0 VVIH - 6.0 V VIL - 0	0	В	uA	Vec
18	TPLH	Vco - 4.5 VVIH = 4.5 V VIL = 0	1	60	n3	TUO

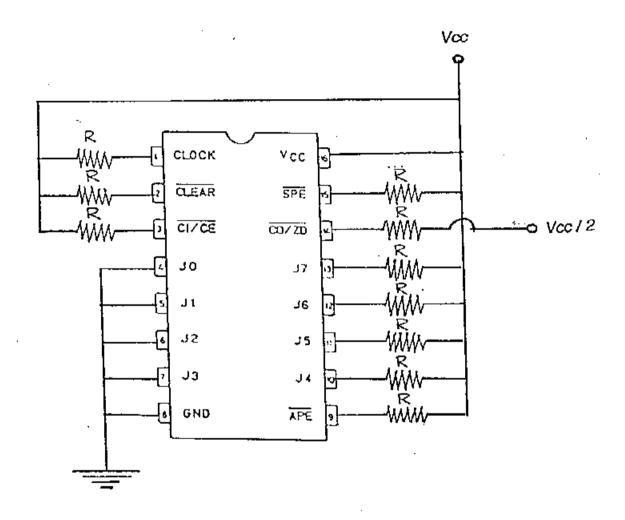
TABLE IV: Summary of Electrical Measurements After
Total Dose Exposures and Annealing Steps for 54HC40103 1/

				Total Dose Exposure (TDE) (krads)										Anneal		Anneal	
				0		5		10		15		20		168 hrs @25°C		168 hrs @+100°C	
	Spec. Limits		(Pre-Rad.)									sd	mean sd		mean s		
parameters		min	max	mean	sđ	mean	sd	mean	sd	mean	8d	mean	30			F	
UNC1				₽		P.		P		2		P.		P		P	
UNC2				P		2		P		P		P	_	P		P	
UNC3				P		P		P	0	2.00	.01	1.99	.01	1.99	.01	2,00	.02
VOH1	V	1.9		2.00		2,00	0	2.00 4.51	_ <del>0</del> _	4.50	0	4.50	.01	4.50	.01	4 50	_01
VOH2	V	4.4		4,51	0	4,51	.01	7	.01	6.00	.01	5.99	0	5.99	.02	5,99	-02
VOH3	V	5.9		6.00	.01_	6.01	0	6.01 4.33	.01	4,32	.01	4.31	.01	4.29	.01	4.32	.0:
VOB4	V	3.98		4.31	.01	4.33	.01	5.82	.01	5.82	.01	5.79	.02	5.79	0	5.80	.0
VOH5	V	5.48		5.81	-01	5.82 3.55	.09	3.53	.12	4.15	.31	1984	12	1998	18	2003	16
VOL1	V	0	100	3.56	.06	3.54	.59	4.04	1.4	4.89	1.2	6.56	2.2	9.95	6.6	5,96	1.
VOL2	<u>v</u>	0	100	3.28	0.3	5,34	2.0	6.23	3.7	7.00	2.3	8.59	3.4	14.24	10	8.03	1.
NOT3	<u>v</u>		100	4.96	2.0	131.6	5.2	131.1	7.5	129.9	1.7	134.9	7.9	142.5	15	131.4	
VOL4	<u>V</u>		260	135.8	2.5	136.8		137.8	11	36.4	3.3	142.5	10	153.3	21	138.5	
VOL5	v	0	260	140.9	1.8	130.0	-	0	-	3 15	0.1	0		1.56	1.8	3.48	0.2
IIH	nA	00	100	1.54		0		Ö	-	o		0	<del>-</del>	. 0		C	<u> </u>
IIL	nA	<del>_</del> -	0_	0059	0	14.61	3.5	240.5	33	956.9	106	1820	245	1636	221	1274	16
ICCH	uA.		8	.002		13.05		212.6		1052		2589	101	2360	94	1828	66
ICCL	uA.		<del></del>	,	1.1	31.9	.85	30.5	0.9	29.9		8,0E		23.9	14	30.9	1.
TPLH	ns	1	60	33.1	1.1	Learning.		25.809.56	- 10	Pri/consession		1 100 11 11 11					

<sup>1/</sup> The mean and standard deviation values were calculated over the four parts irradiated in this testing.

The control sample remained constant throughout the testing and is not included in this table.

Figure 1. Radiation Bias Circuit for 54HC40103



R = 2.2 Kohms + / - 5%, @ 1/2 W Vcc = 5.0 V + / - 10%